

Notice of References Cited	Application/Control No. 09/577,209	Applicant(s)/Patent Under Reexamination VALENZUELA ET AL.	
	Examiner Ricky D. Shafer	Art Unit 2872	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Korte, "High-throughput replica optics"; Applied Optics; Vol. 27, No. 8; 15 April 1988; pp 1440-1446
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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